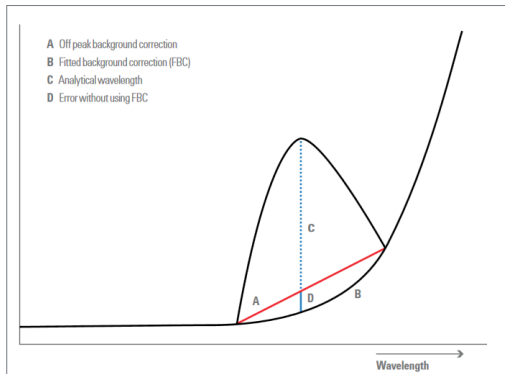


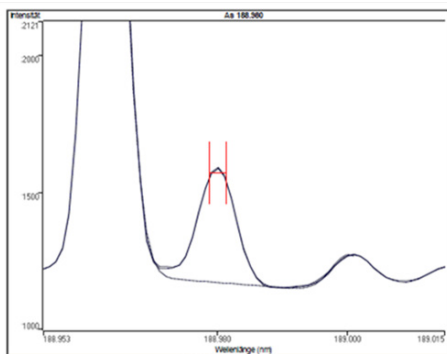
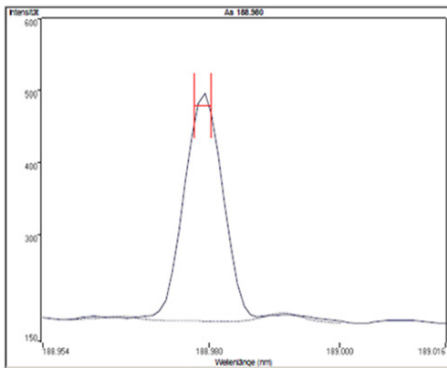


ICP-OES Background and Interference Removal

Accurate. Easy. Reliable.



Fitted Background Correction calculates the true background signal, improving accuracy and saving time during method development.



Fitted Background Correction automatically provides accurate background correction, even for spectra where setting off-peak correction point would be challenging (lower).

ICP Expert software algorithms that deliver accurate, reliable results

Automated algorithms for ICP-OES background correction:

- Fitted Background Correction (FBC) for accurate and fast correction of simple and complex backgrounds, and
- Fast Automated Curve Fitting Technique (FACT), for highly complex backgrounds

Fitted Background Correction (FBC)

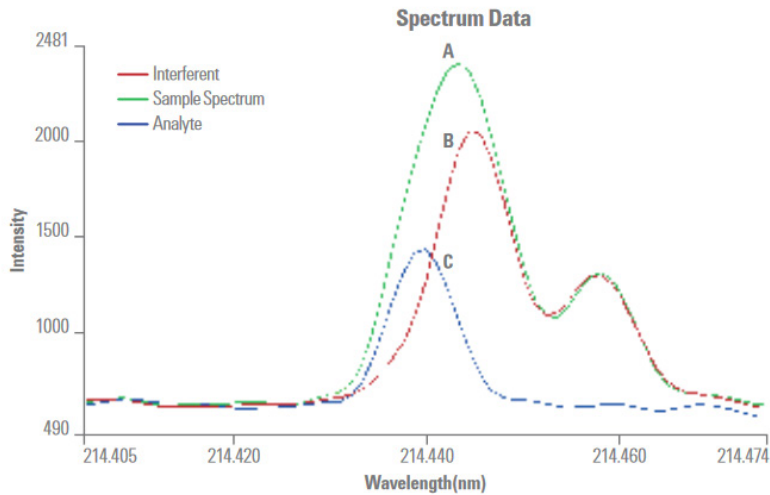
Features

- Utilizes a sophisticated mathematical algorithm to model the true background signal under the analyte peak
- Automatically provides accurate correction of both simple and complex background structures
- Easily handles background for spectra where setting off-peak correction points is difficult
- Takes the guess work out of setting off-peak background correction points

Benefits

- Save time by not needing to check every sample for appropriate off-peak background markers. The Fitted Background Correction algorithm ensures every sample has appropriate correction.
- The Fitted Background Correction algorithm adapts the baseline to each individual sample. This improves detection limits and data quality, and reduces over-corrections, common when using off peak background correction.

FACT (Fast Automated Curve-fitting Technique)



Resolve spectral interference with FACT

Resolution of the difficult Fe interference at Cd 214.438 nm. Shown are:

- A. Appearance of the peaks in a soil sample,
- B. FACT model of the interference,
- C. Corrected signal for the Cd analyte.

Element & wavelength (nm)	Off-peak MDL (ppm)	Fitted MDL	FACT MDL (ppm)
Pb 261.618	1.69	1.363	0.119

Method Detection Limits determined for Pb 261.618 nm in gasoline diluted in kerosene on an Agilent ICP-OES using Off-peak, Fitted and FACT background correction techniques. Using FACT to model the complex background structure of gasoline in kerosene, a far more accurate measurement of the analyte signal is possible, lowering the detection limit.

Features

- Simpler, more convenient alternative to inter-element correction (IEC) to remove complex spectral interferences
- Accurately corrects for spectral interferences by applying a highly sophisticated, spectral modeling technique
- Provides accurate background correction for highly-complex background structures where other techniques are unsuitable

Benefits

- Easy-to-use: create FACT models by measuring expected components separately (typically blank solution, pure analyte solution and pure interferent solutions)
- Save time: FACT models can be created either before or after analytical data collection, eliminating further sample preparation, sample re-analysis and erroneous data analysis
- Improve detection limits for challenging samples, such as organic solvents, which results in complex background structures

For more information, visit:

www.agilent.com/chem/5800icpoes

This information is subject to change without notice.

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